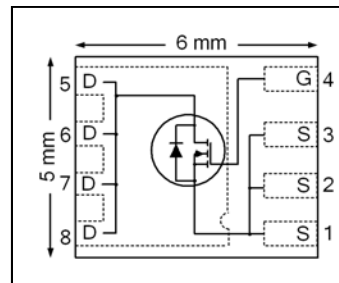


HEXFET® Power MOSFET

$V_{DSS}$	25	V
$R_{DS(on) \max}$ (@ $V_{GS} = 10V$ )	0.95	mΩ
(@ $V_{GS} = 4.5V$ )	1.25	
$Qg$ (typical)	46.0	nC
$I_D$ (@ $T_C(Bottom) = 25^\circ C$ )	100 <sup>Ⓣ</sup>	A



**Applications**

- Synchronous Rectifier MOSFET for Sync Buck Converters
- Secondary Synchronous Rectifier MOSFET for isolated DC-DC converters
- Active ORing and Hot Swap
- Battery Operated DC Motor Inverters

**Features**

Low $R_{DS(on)}$ (<0.95 mΩ)
Low Thermal Resistance to PCB (<0.8°C/W)
Low Profile (<0.9 mm)
Industry-Standard Pinout
Compatible with Existing Surface Mount Techniques
RoHS Compliant, Halogen-Free
MSL1, Industrial Qualification

results in  
 ⇒

**Benefits**

Lower Conduction Losses
Enable better thermal dissipation
Increased Power Density
Multi-Vendor Compatibility
Easier Manufacturing
Environmentally Friendlier
Increased Reliability

Base part number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
IRFH4201PbF	PQFN 5mm x 6 mm	Tape and Reel	4000	IRFH4201TRPbF

**Absolute Maximum Ratings**

	Parameter	Max.	Units
$V_{GS}$	Gate-to-Source Voltage	± 20	V
$I_D @ T_A = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	49	A
$I_D @ T_{C(Bottom)} = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	326 <sup>Ⓣ</sup>	
$I_D @ T_{C(Bottom)} = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	206 <sup>Ⓣ</sup>	
$I_D @ T_{C(Bottom)} = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Source Bonding Technology Limited)	100 <sup>Ⓣ</sup>	
$I_{DM}$	Pulsed Drain Current <sup>①</sup>	400	
$P_D @ T_A = 25^\circ C$	Power Dissipation <sup>⑤</sup>	3.5	W
$P_D @ T_{C(Bottom)} = 25^\circ C$	Power Dissipation	156	
	Linear Derating Factor	0.028	W/°C
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to + 150	°C

Notes <sup>①</sup> through <sup>⑦</sup> are on page 8

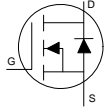
**Static @ T<sub>J</sub> = 25°C (unless otherwise specified)**

	Parameter	Min.	Typ.	Max.	Units	Conditions
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	25	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temp. Coefficient	—	20	—	mV/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	—	0.70	0.95	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 50A ③
		—	0.97	1.25		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 50A ③
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.1	1.6	2.1	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 150μA
ΔV <sub>GS(th)</sub>	Gate Threshold Voltage Coefficient	—	-5.9	—	mV/°C	
I <sub>DSS</sub>	Drain-to-Source Leakage Current	—	—	1.0	μA	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	—	—	100	nA	V <sub>GS</sub> = 20V
	Gate-to-Source Reverse Leakage	—	—	-100		V <sub>GS</sub> = -20V
g <sub>fs</sub>	Forward Transconductance	175	—	—	S	V <sub>DS</sub> = 13V, I <sub>D</sub> = 50A
Q <sub>g</sub>	Total Gate Charge	—	94.0	—	nC	V <sub>GS</sub> = 10V, V <sub>DS</sub> = 13V, I <sub>D</sub> = 50A
Q <sub>g</sub>	Total Gate Charge	—	46.0	69.0	nC	V <sub>DS</sub> = 13V V <sub>GS</sub> = 4.5V I <sub>D</sub> = 50A
Q <sub>gs1</sub>	Pre-V <sub>th</sub> Gate-to-Source Charge	—	11.0	—		
Q <sub>gs2</sub>	Post-V <sub>th</sub> Gate-to-Source Charge	—	6.4	—		
Q <sub>gd</sub>	Gate-to-Drain Charge	—	16.0	—		
Q <sub>godr</sub>	Gate Charge Overdrive	—	12.6	—		
Q <sub>sw</sub>	Switch Charge (Q <sub>gs2</sub> + Q <sub>gd</sub> )	—	22.4	—		
Q <sub>oss</sub>	Output Charge	—	46.0	—	nC	V <sub>DS</sub> = 16V, V <sub>GS</sub> = 0V
R <sub>G</sub>	Gate Resistance	—	0.9	2.7	Ω	
t <sub>d(on)</sub>	Turn-On Delay Time	—	20	—	ns	V <sub>DD</sub> = 13V, V <sub>GS</sub> = 4.5V I <sub>D</sub> = 50A R <sub>G</sub> = 1.8Ω
t <sub>r</sub>	Rise Time	—	43	—		
t <sub>d(off)</sub>	Turn-Off Delay Time	—	24	—		
t <sub>f</sub>	Fall Time	—	19	—		
C <sub>iss</sub>	Input Capacitance	—	6100	—	pF	V <sub>GS</sub> = 0V V <sub>DS</sub> = 13V f = 1.0MHz
C <sub>oss</sub>	Output Capacitance	—	1700	—		
C <sub>rss</sub>	Reverse Transfer Capacitance	—	450	—		

**Avalanche Characteristics**

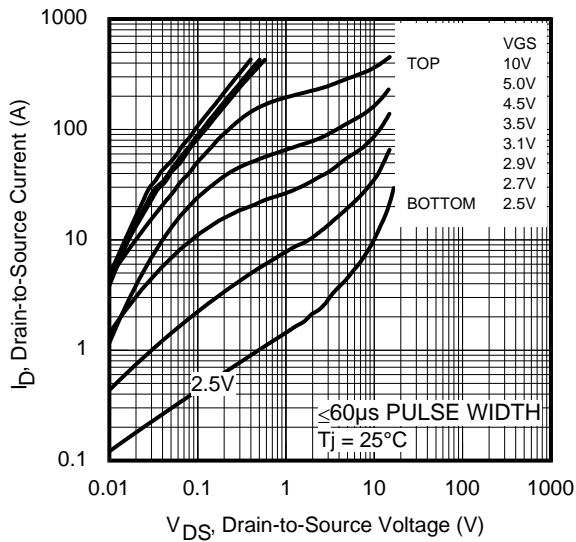
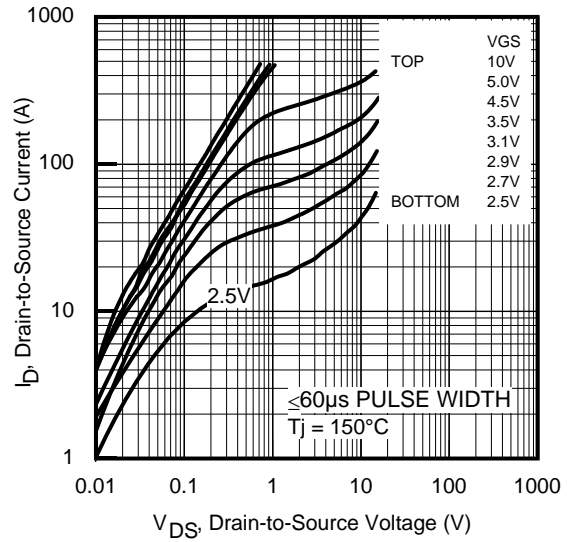
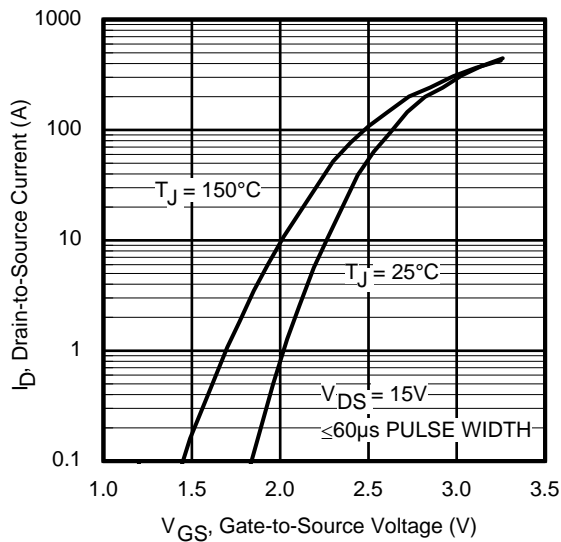
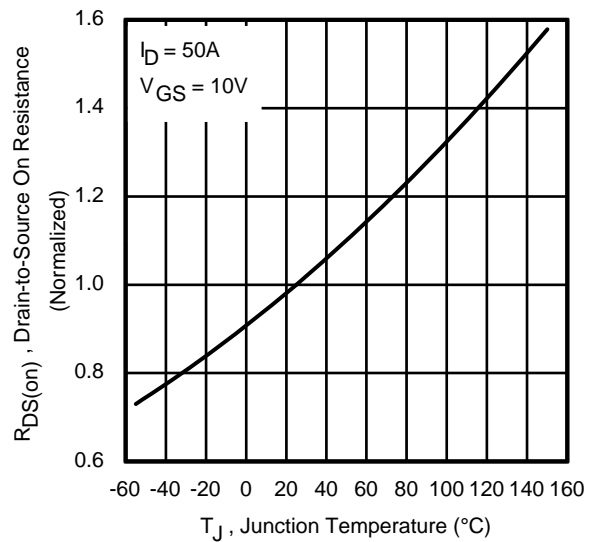
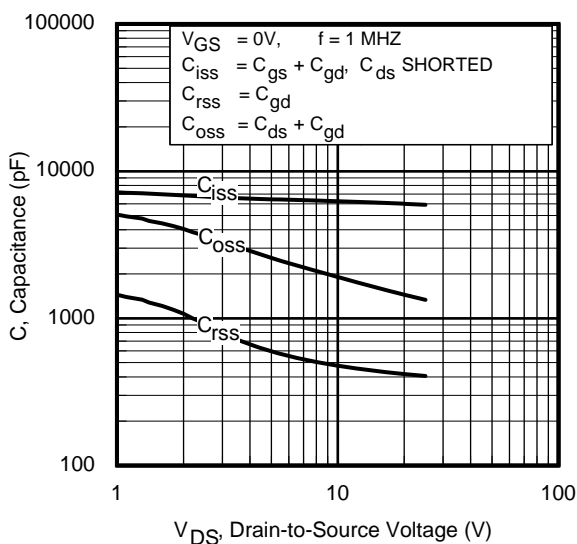
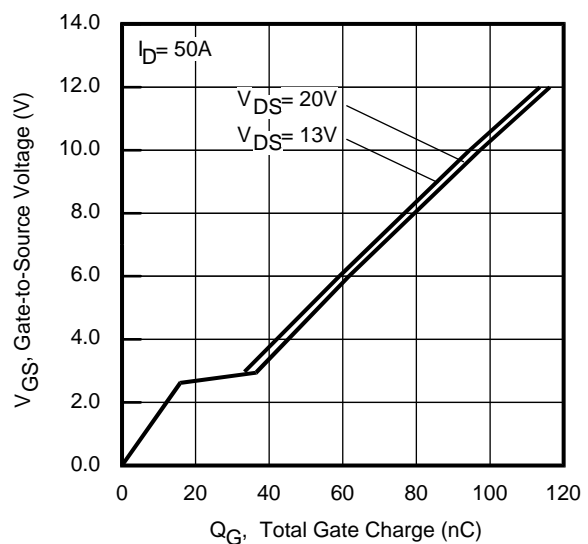
	Parameter	Typ.	Max.
E <sub>AS</sub>	Single Pulse Avalanche Energy ②	—	478
I <sub>AR</sub>	Avalanche Current ①	—	50

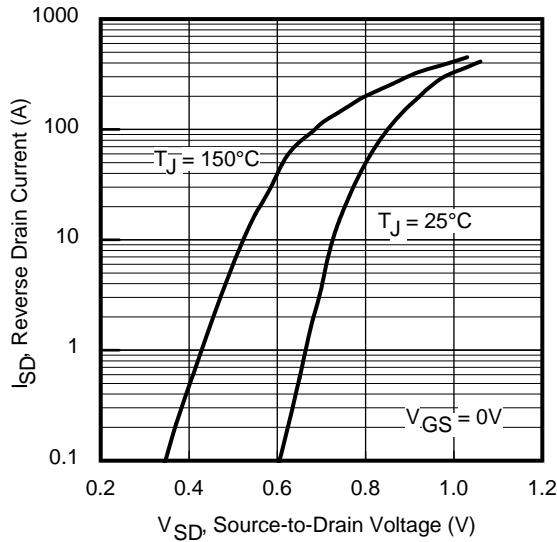
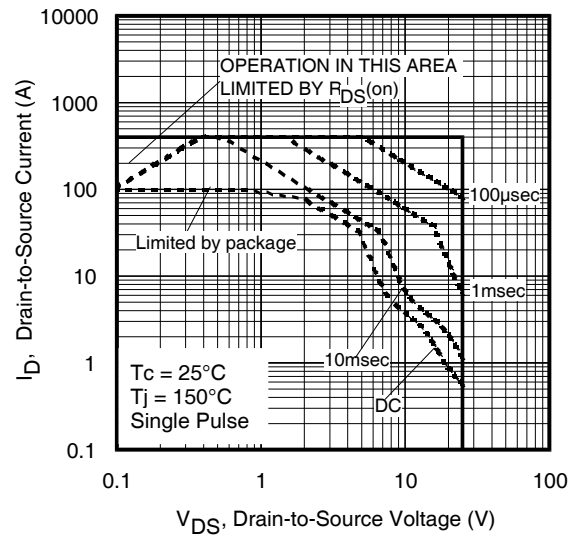
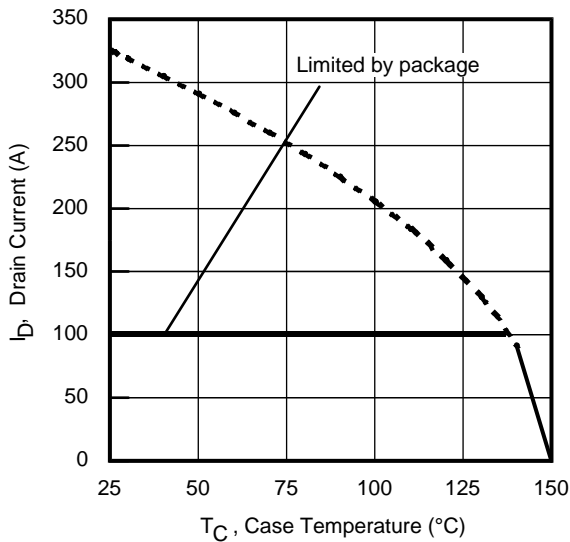
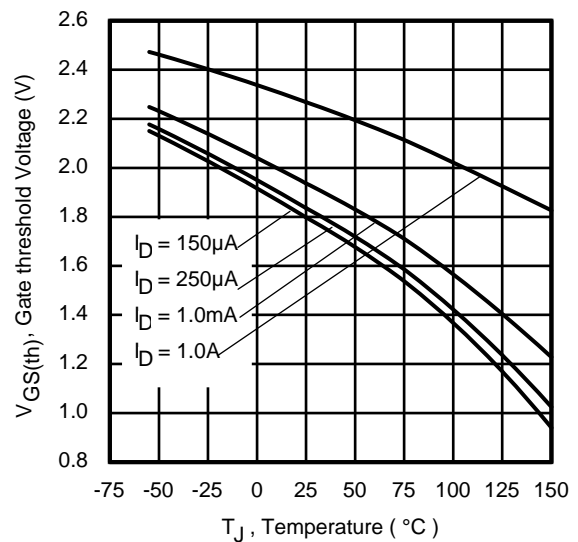
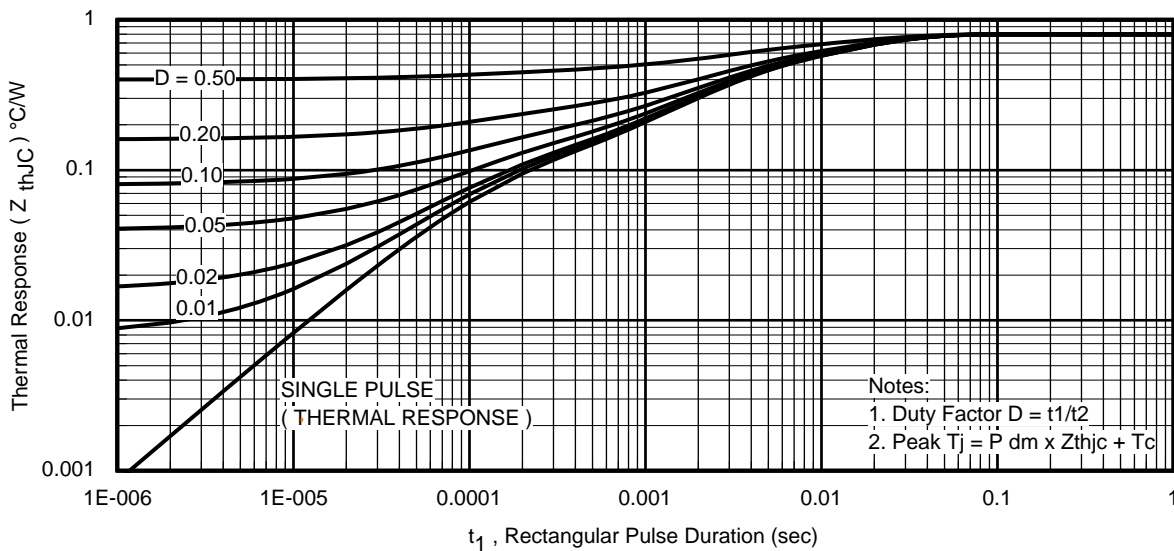
**Diode Characteristics**

	Parameter	Min.	Typ.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	100 <sup>⑦</sup>	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	—	—	400		
V <sub>SD</sub>	Diode Forward Voltage	—	—	1.0	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 50A, V <sub>GS</sub> = 0V ③
t <sub>rr</sub>	Reverse Recovery Time	—	31	47	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 50A, V <sub>DD</sub> = 13V
Q <sub>rr</sub>	Reverse Recovery Charge	—	84	126	nC	di/dt = 400A/μs ③

**Thermal Resistance**

	Parameter	Typ.	Max.	Units
R <sub>θJC</sub> (Bottom)	Junction-to-Case ④	—	0.8	°C/W
R <sub>θJC</sub> (Top)	Junction-to-Case ④	—	18	
R <sub>θJA</sub>	Junction-to-Ambient ⑤	—	36	
R <sub>θJA</sub> (<10s)	Junction-to-Ambient ⑤	—	22	


**Fig 1. Typical Output Characteristics**

**Fig 2. Typical Output Characteristics**

**Fig 3. Typical Transfer Characteristics**

**Fig 4. Normalized On-Resistance vs. Temperature**

**Fig 5. Typical Capacitance vs. Drain-to-Source Voltage**

**Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage**


**Fig 7.** Typical Source-Drain Diode Forward Voltage

**Fig 8.** Maximum Safe Operating Area

**Fig 9.** Maximum Drain Current vs. Case Temperature

**Fig 10.** Drain-to-Source Breakdown Voltage

**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case

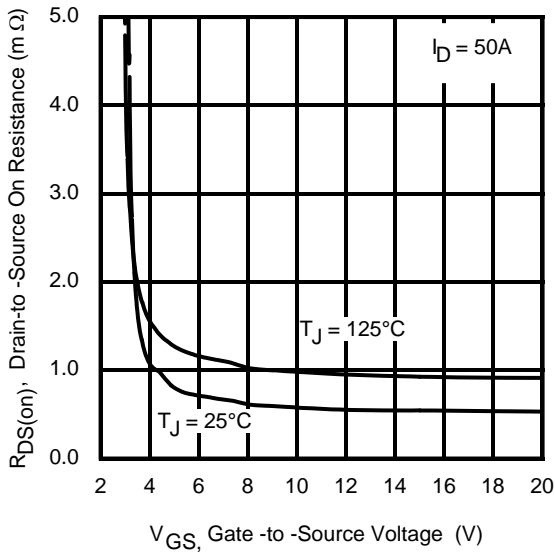


Fig 12. On- Resistance vs. Gate Voltage

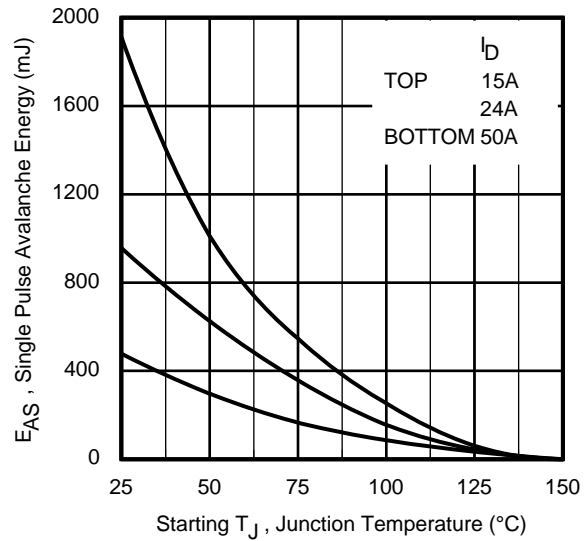


Fig 13. Maximum Avalanche Energy vs. Drain Current

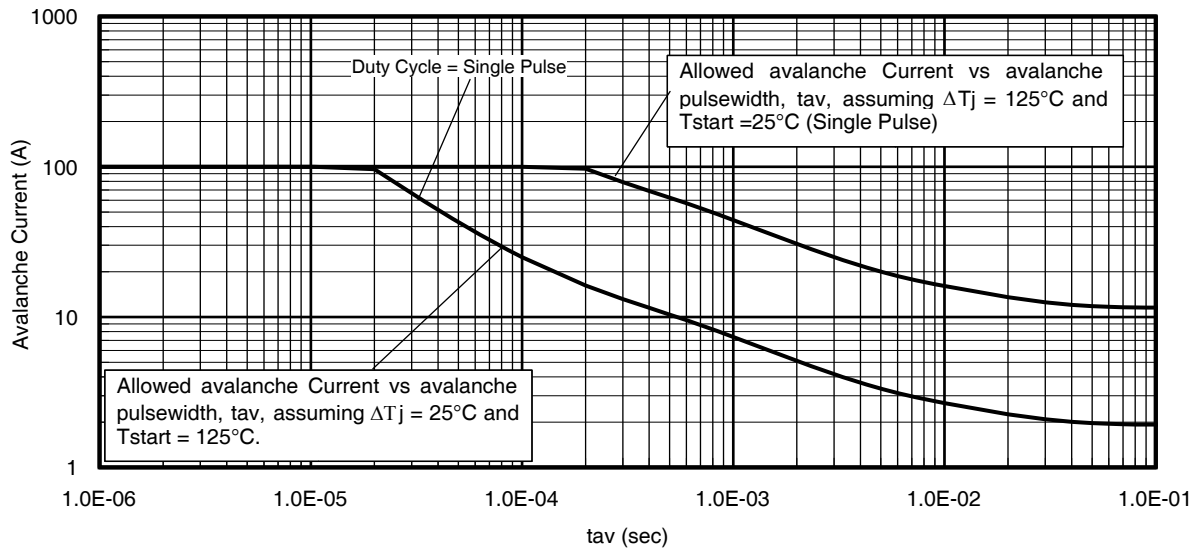
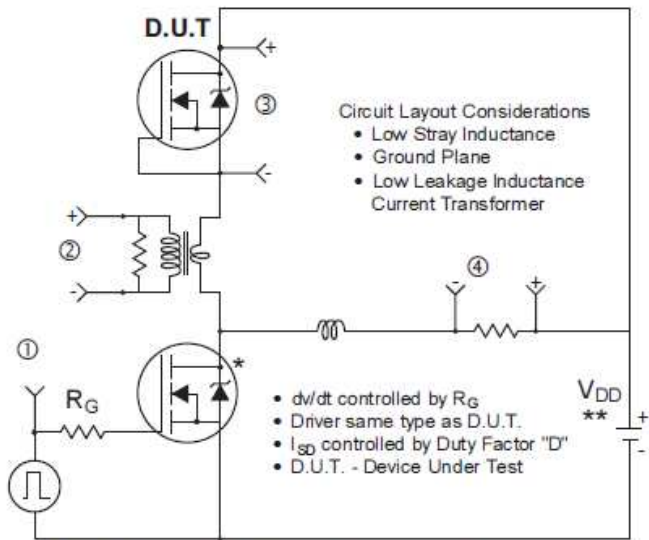


Fig 14. Typical Avalanche Current vs. Pulsewidth



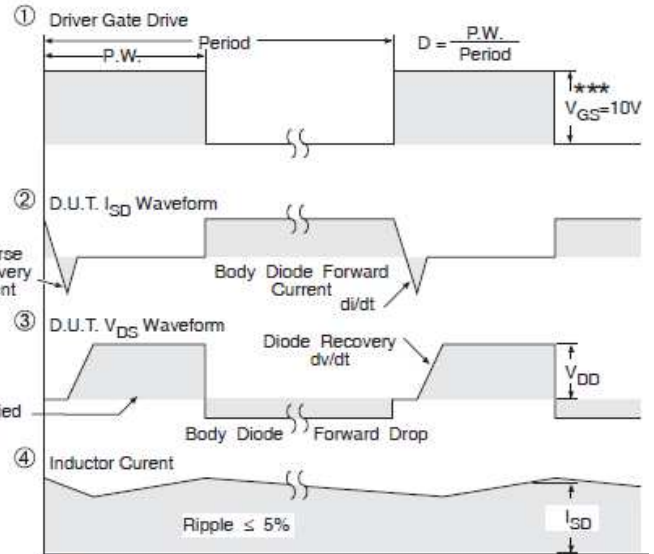
- Circuit Layout Considerations
- Low Stray Inductance
  - Ground Plane
  - Low Leakage Inductance Current Transformer

- $dv/dt$  controlled by  $R_G$
- Driver same type as D.U.T.
- $I_{SD}$  controlled by Duty Factor "D"
- D.U.T. - Device Under Test

\* Use P-Channel Driver for P-Channel Measurements

\*\* Reverse Polarity for P-Channel

Fig 15. Peak Diode Recovery  $dv/dt$  Test Circuit for N-Channel HEXFET® Power MOSFETs



\*\*\*  $V_{GS} = 5V$  for Logic Level Devices

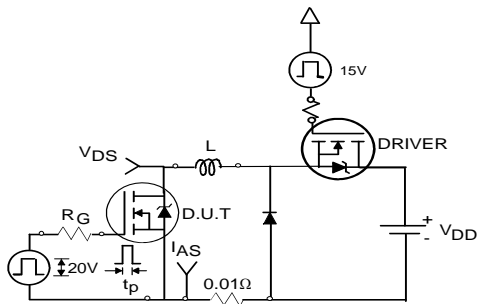


Fig 16a. Unclamped Inductive Test Circuit

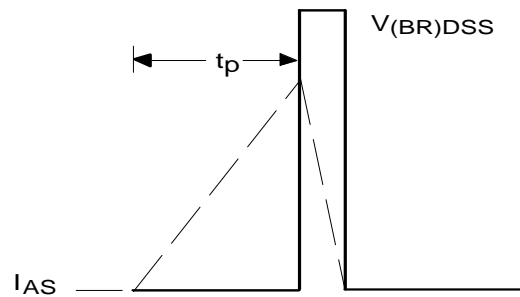


Fig 16b. Unclamped Inductive Waveforms

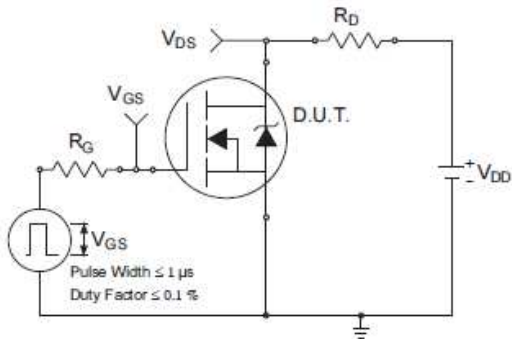


Fig 17a. Switching Time Test Circuit

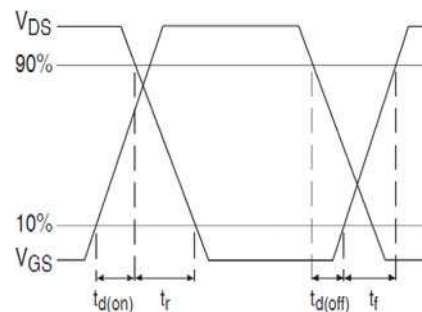


Fig 17b. Switching Time Waveforms

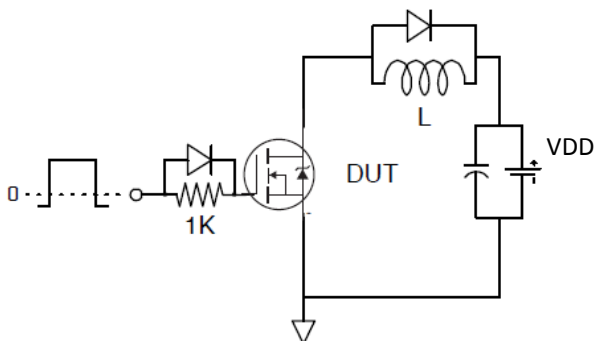


Fig 18. Gate Charge Test Circuit

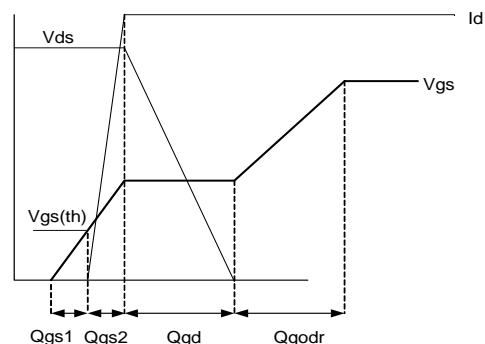
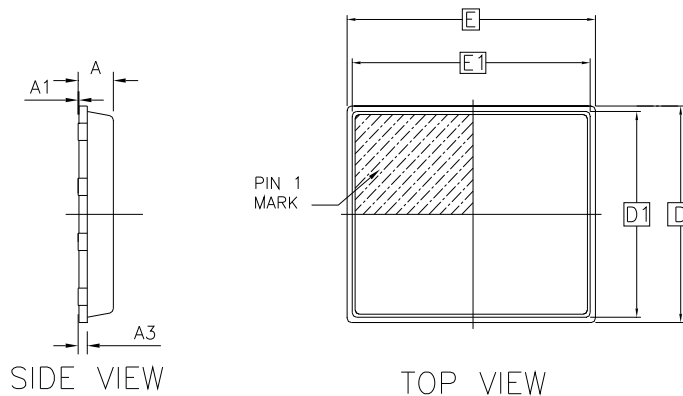
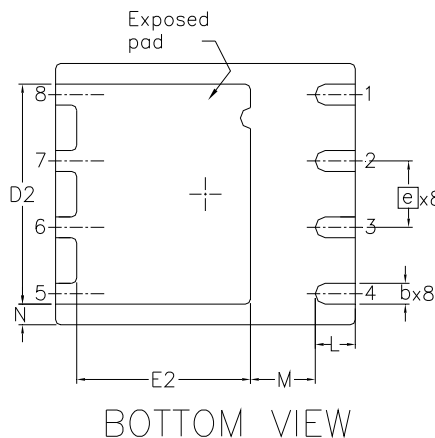


Fig 19. Gate Charge Waveform

PQFN 5x6 Outline "B" Package Details

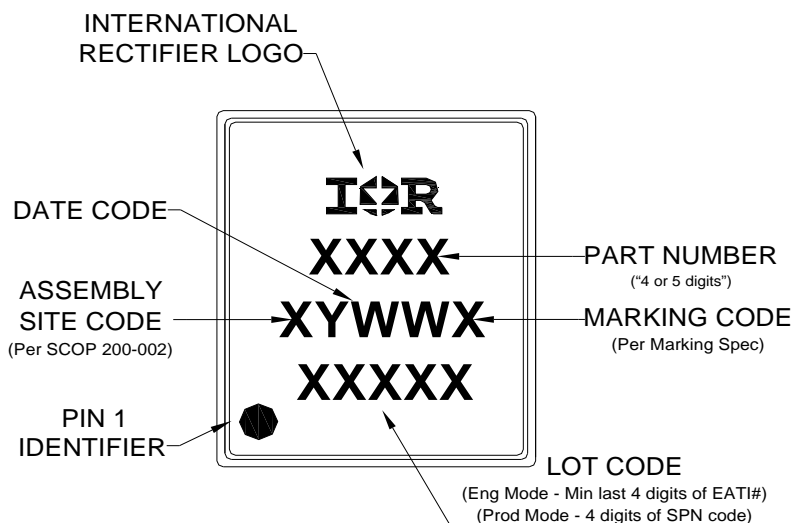


OUTLINE PQFN 5x6B			
DIM SYMBOL	MIN	NOM	MAX
A	0.80	0.83	0.90
A1	0	0.020	0.05
A3		0.20	REF
b	0.35	0.40	0.47
D		5.00	BSC
D1		4.75	BSC
D2	4.10	4.21	4.30
e		1.27	BSC
E		6.00	BSC
E1		5.75	BSC
E2	3.38	3.48	3.58
L	0.70	0.80	0.90
M		1.30	REF
N		0.40	REF

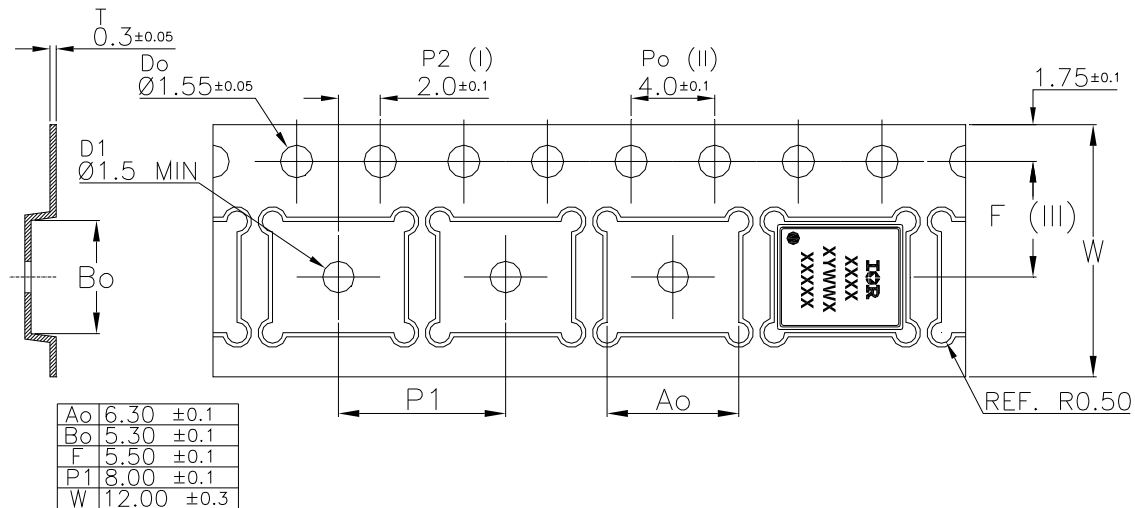


For more information on board mounting, including footprint and stencil recommendation, please refer to application note AN-1136: <http://www.irf.com/technical-info/appnotes/an-1136.pdf>  
 For more information on package inspection techniques, please refer to application note AN-1154: <http://www.irf.com/technical-info/appnotes/an-1154.pdf>

PQFN 5x6 Outline "B" Part Marking



Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

**PQFN 5x6 Outline "B" Tape and Reel**


Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

**Qualification Information†**

<b>Qualification Level</b>	Industrial (per JEDEC JESD47F <sup>††</sup> guidelines)	
<b>Moisture Sensitivity Level</b>	PQFN 5mm x 6mm	MSL1 (per JEDEC J-STD-020D <sup>††</sup> )
<b>RoHS Compliant</b>	Yes	

† Qualification standards can be found at International Rectifier's web site: <http://www.irf.com/product-info/reliability>

†† Applicable version of JEDEC standard at the time of product release.

**Notes:**

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting  $T_J = 25^\circ\text{C}$ ,  $L = 0.38\text{mH}$ ,  $R_G = 50\Omega$ ,  $I_{AS} = 50\text{A}$ .
- ③ Pulse width  $\leq 400\mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- ④  $R_\theta$  is measured at  $T_J$  of approximately  $90^\circ\text{C}$ .
- ⑤ When mounted on 1 inch square PCB (FR-4). Please refer to AN-994 for more details:  
<http://www.irf.com/technical-info/appnotes/an-994.pdf>
- ⑥ Calculated continuous current based on maximum allowable junction temperature.
- ⑦ Current is limited to 100A by source bonding technology.

**Revision History**

Date	Comments
05/17/2013	<ul style="list-style-type: none"> <li>• Updated package 3D drawing, on page 1.</li> <li>• Added Continuous Drain Current limited by source bonding technology, on page 1.</li> <li>• Divided note 6 into note 6 &amp; 7, on page 8.</li> </ul>
01/15/2013	<ul style="list-style-type: none"> <li>• Release of final data sheet.</li> </ul>